

Surface and Thickness Measurement in the Targetlab of GSI

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For characterization of targets and foils prepared at the target laboratory as well as for characterization of e.g. degrader or windows of internal customers different analytical devices are available. Besides a lot of standard the target laboratory of GSI holds a 3D-measurement system (MicroProf®) equipped with optical sensors for measuring surface parameter as well as total thickness variations contact-free.

In the talk the measuring principle as well as the possibilities and features of the MicroProf®-system are explained and some different applications are shown.

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